Special Issue

Digitalization of Metrology

Message from the Guest Editors

The digitalization of metrology is a hot topic in the area of international measurement. BIPM, ISO, IEC, and other international orgnizations are aiming towards the Digital Transformation of metrology. NIST, PTB , NIM, and other national institutes are all developing digitalizations of metrology. The digitalization of metrology is maintaining and building confidence in the accuracy and global comparability of measurements.   The aim of the Special Issue focuses on frontier research on the digitalization of metrology. Any research on the DT of metrology or measurements is invited to be submitted to this Special Issue; Research areas may include (but are not limited to) the following:

- Metrology digitalization research:
- Digital representations of physical quantities and units of measurement such as D-SI;
- Computations with physical quantities;
- Information retrieval and knowledge representations (semantics, ontologies, etc.).

We look forward to receiving your contributions.

Guest Editors

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Deadline for manuscript submissions

closed (16 December 2024)

Electronics

an Open Access Journal by MDPI

Impact Factor 2.6
CiteScore 6.1

mdpi.com/si/185793

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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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